



OptoTech

μ Shape OWI

Phaseshifting Analysis Software



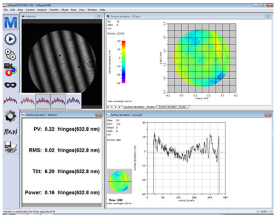
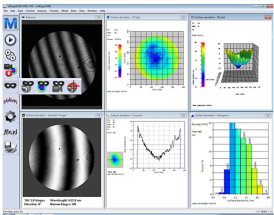
μ Shape OWI is a versatile tool for quality control in optical manufacturing and testing labs. It analyzes deviations from the nominal shape and visualizes the results for direct comparison with design specifications. The software is user-friendly, customizable, and seamlessly integrates into your workflow. It controls and documents measurement processes, ensures transparency, and allows data export for CNC control. Powerful algorithms enable precise analysis and flexible adjustments to your measurement tasks.



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Technical Data

	μShape OWI
Application	Phaseshifting Analysis Software for Interferometer
Disclaimer	All data are subject to change without notice. Please verify details with OptoTech.





Highlights

- Different program modes: Separate display of the calibration and measurement process in easily switchable program modes with integrated live camera image
- Templates: Simple pre-configuration for a wide range of measurement tasks, evaluation and storage in the form of templates
- Data export: Export of individual parameters as a text file or specific data fields in binary form for further external processing
- Protocol function: Individual measurement protocols with different graphics and variable measurement data display for quality documentation
- User levels: Different user levels with different access rights
- Online help: Comprehensive and context-sensitive online help

Performance Characteristics

- Measurement parameters: Setting of all measurement parameters according to the respective measurement arrangement, separately for calibration and test item measurement in each case
- Masks: Set geometric elements (circles, ellipses, rectangles, squares and polygons) as inner or outer masks in any combination
- Wavefront parameters: Setting of all parameters required for the calculation of wavefronts, e.g. subtraction of calibration data, activation of various smoothing and hole-closing methods, compensation of adjustment errors for flat or spherical test specimens
- Configuration: Scaling of the measuring field in length units; conversion of the results from measuring wavelength to drawing wavelength
- Display: Graphical display of the data fields (intensity, phase image, measurement results) as a sectional, 2D or 3D image, as well as all parameters and statistical values in tabular form. Text display of statistical values, DIN and ISO parameters, Zernike and Seidel coefficients.

Options

Further add-on modules with interesting program extensions such as aspherical compensation, multi-apertures or MTF measurement are available.

These modules can be retrofitted at any time if required.

µShape OWI is supplied complete with a phase shifter adapted to the interferometer (piezo actuator incl. amplifier unit) and a software dongle and is ready for immediate use.